

## 2. Link and Memory Architectures and Technologies

2.1 Links, Thruput/Buffering, Multi-Access Ovrhds

2.2 Memories: On-chip / Off-chip SRAM, DRAM

2.A Appendix: Elastic Buffers for Cross-Clock Commun.

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## 2.2 Memories: On-chip / Off-chip SRAM, DRAM

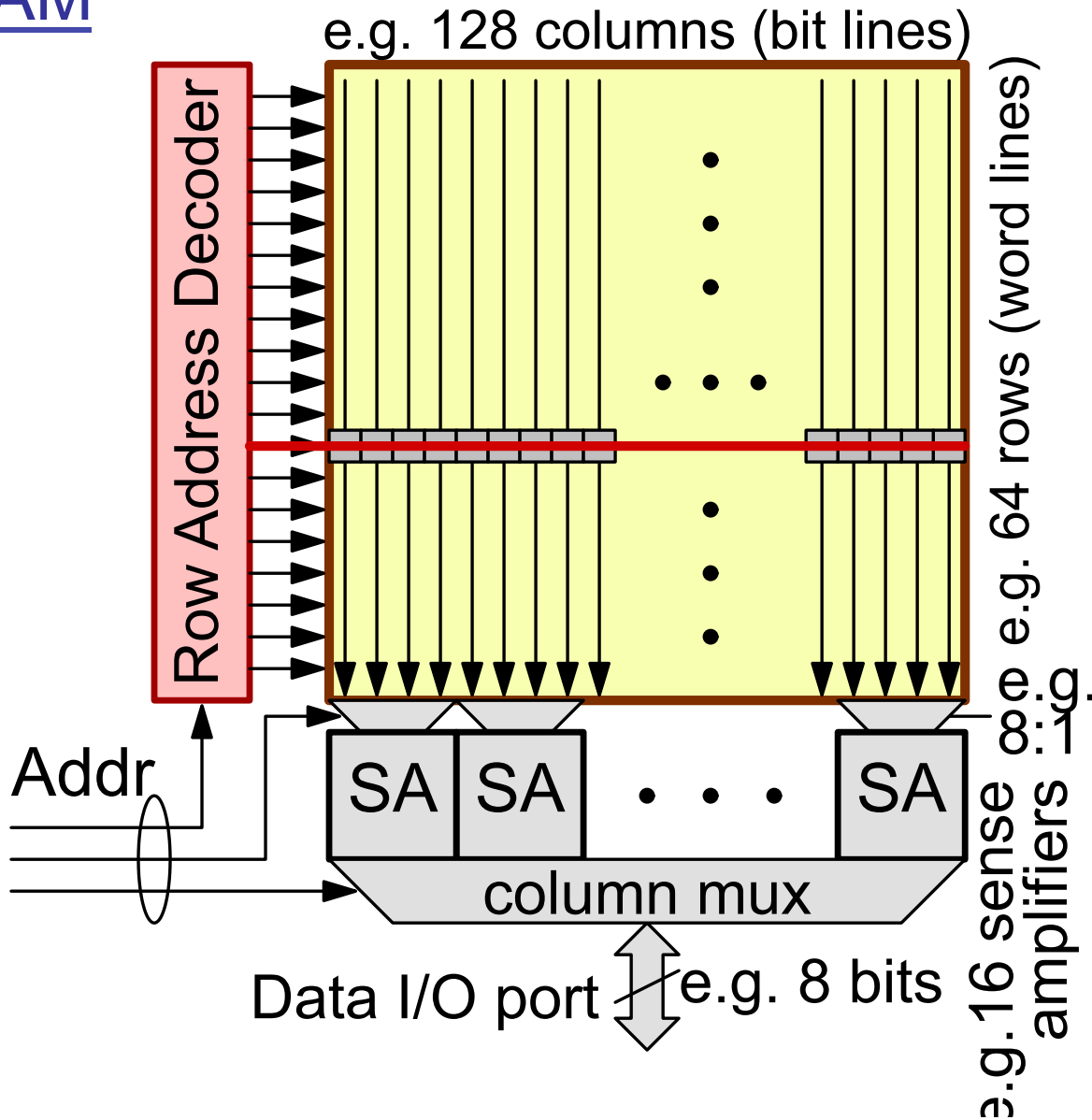
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## 2.2.1 On-Chip SRAM

*Read Cycle Includes:*

- Precharge bit lines
- Decode row address
- Activate word line
  - faster when narrow
- Discharge bit lines
  - faster when short
- Sense amplifiers
  - don't wait for full discharge before telling the result
- Column multiplexors
  - use column address

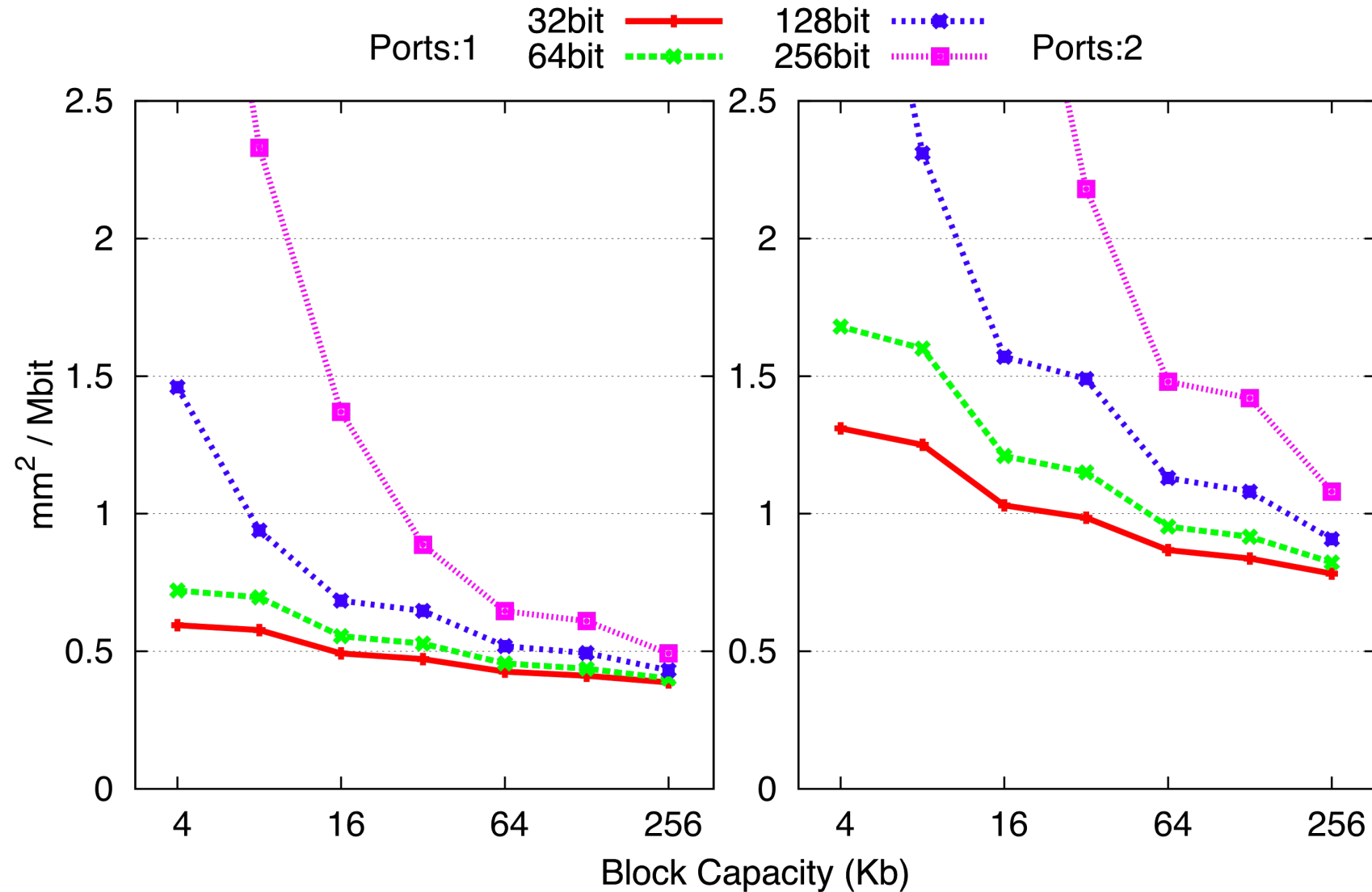


## Sense Amplifiers: Role, Consequences

- Sense amplifiers significantly speed up read access time
  - sense 0-contents soon after bit-line discharge has started
- Sense amplifiers (SA) are large in size
  - can fit only one SA per 2 to 8 columns
  - analog multiplexors before SA select columns to be read
  - digital multiplexors after SA needed for narrow port widths – they result in large blocks being slower when port is too narrow
- Sense amplifiers consume significant energy when activated
  - only activate the block when read data are actually needed
  - power consumption is proportional to access frequency
  - power consumption is proportional to number of sense amp's (increases with port width, or with bit capacity of SRAM)

# On-chip SRAM blocks example (45 nm CMOS): **Area**

Area per Mbit vs Capacity, 45 nm, LSTP, Vdd: 1.1v, Vth: 0.502v

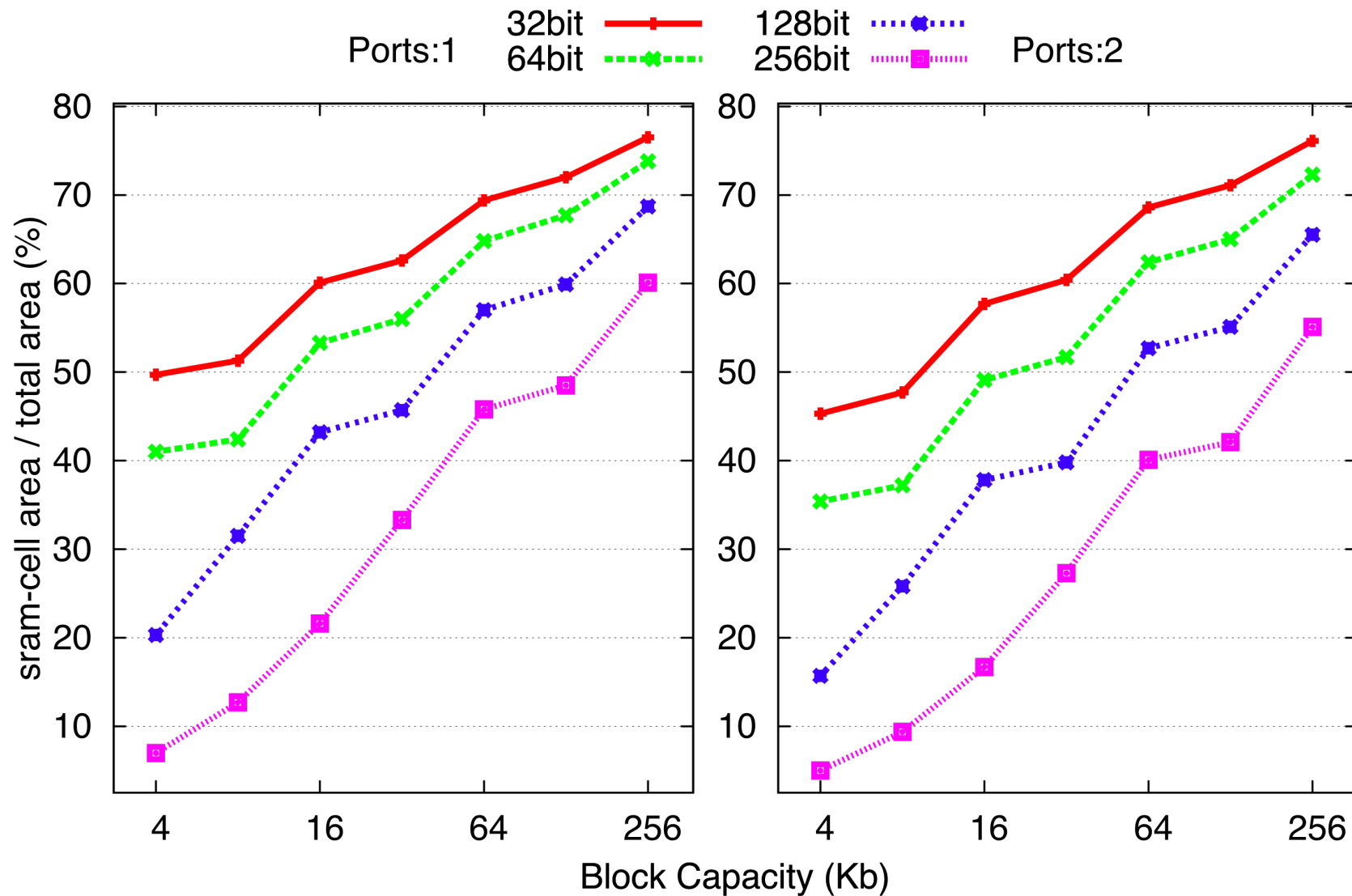


## Area per Megabit: Comments

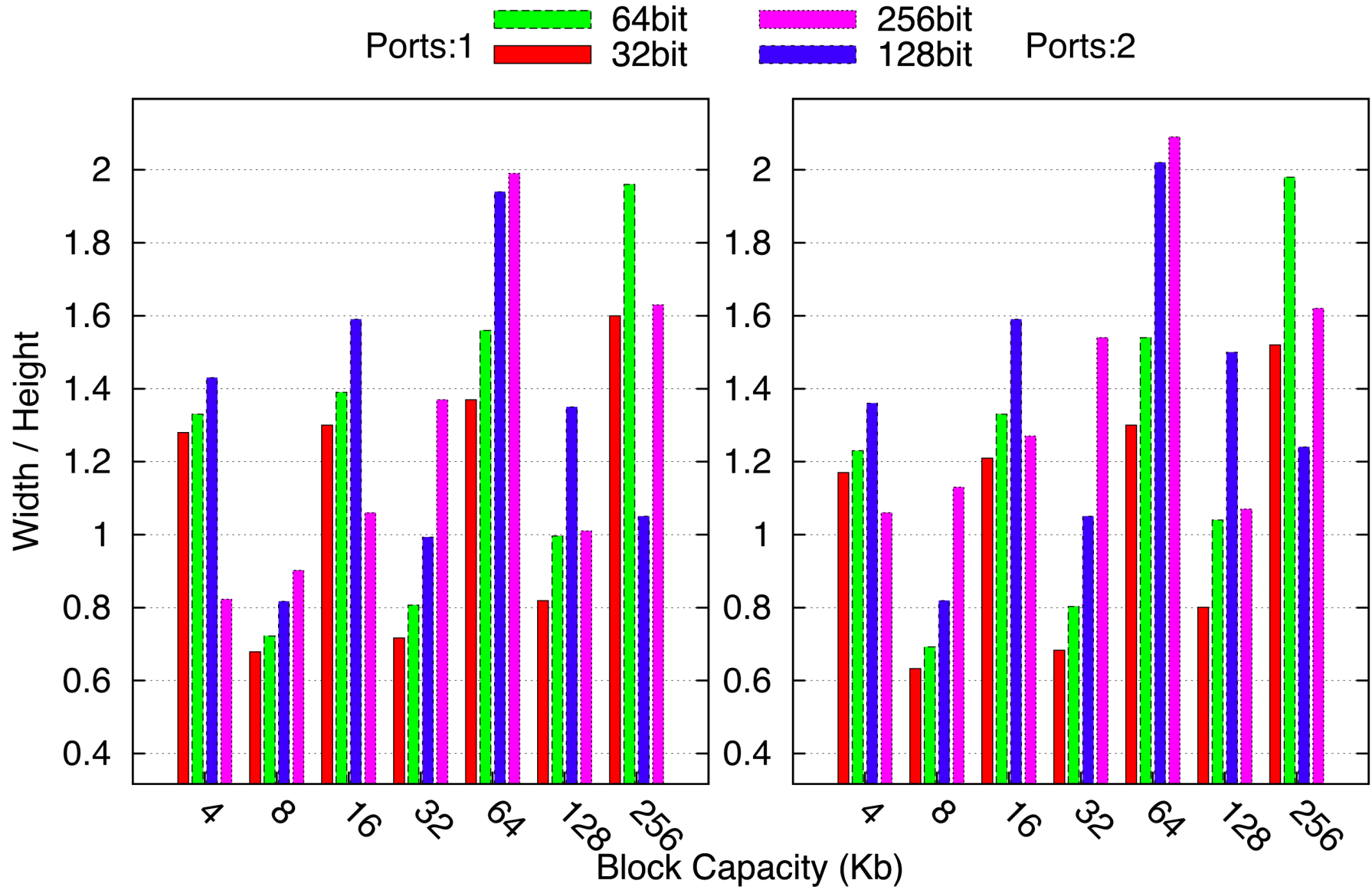
- Values are  $(\mu\text{m})^2/\text{bit} = (\text{mm})^2/\text{Mbit}$
- CACTI estimates, using ITRS 2010 roadmap
- Large blocks are more area-efficient than small ones
  - peripheral overhead (address decoders, column multiplexors, sense amplifiers, power ring) amortized over a larger core
- Port width costs a lot for small blocks
  - more sense amplifiers needed, possibly non-square aspect ratio
  - large blocks need many SA's, for either narrow or wide ports
- Two-port blocks: one *read-only* port and one *write-only* port
- Two-port area is about 2x to 3x the area of one-port SRAM
- Blocks include ECC overhead
- No power ring included in the quoted area numbers

# Core Area as percent of Total Area (45 nm CMOS)

Area Efficiency vs Capacity, 45 nm, LSTP, Vdd: 1.1v, Vth: 0.502v



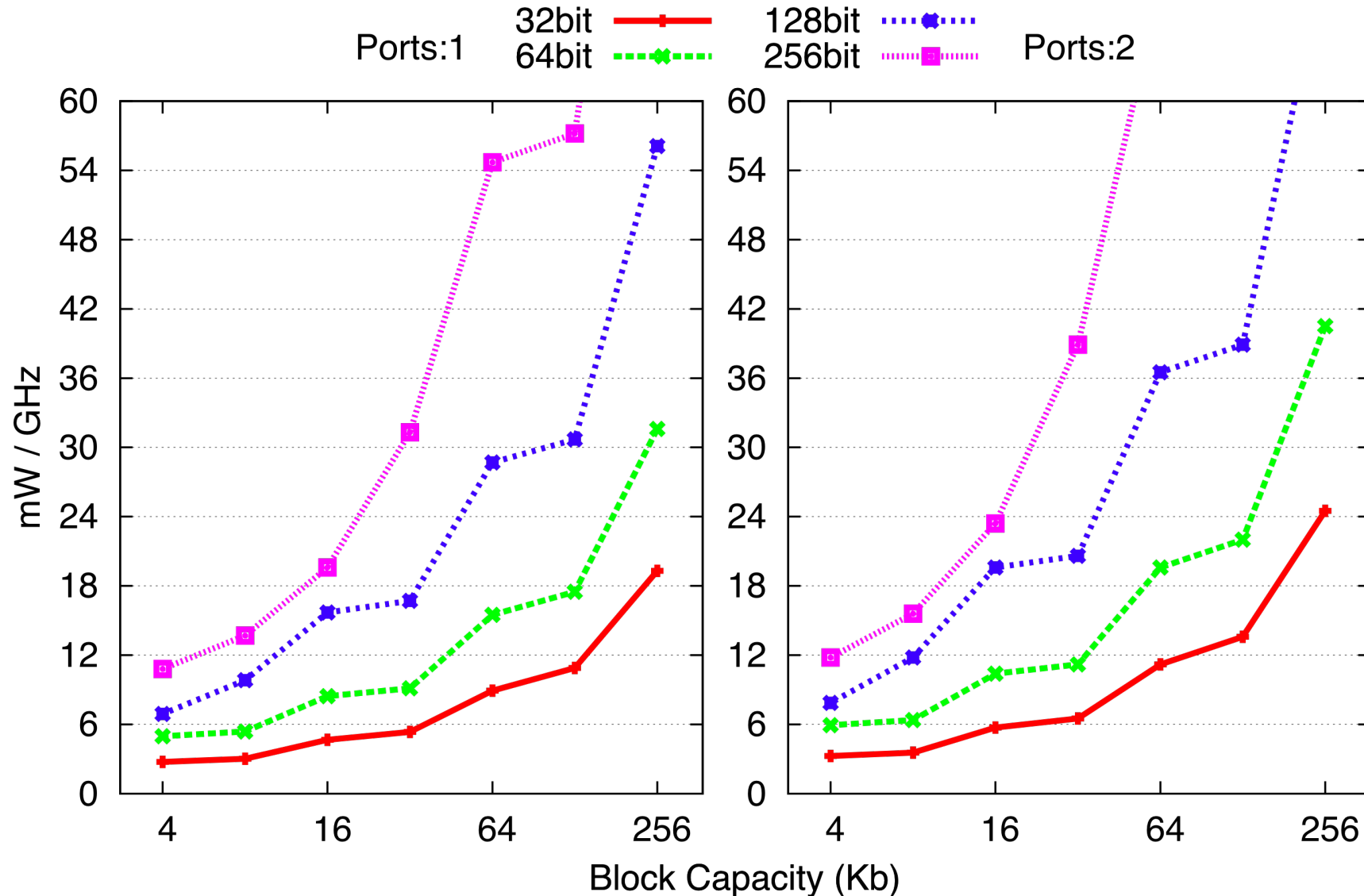
Block aspect ratio vs Capacity, 45 nm, LSTP, Vdd: 1.1v, Vth: 0.502v





# On-chip SRAM (45 nm): Dynamic Power Consumpt'n

Dyn. Power per port for R/W accesses vs Cap., 45 nm, LSTP, V<sub>dd</sub>: 1.1v, V<sub>th</sub>: 0.502v

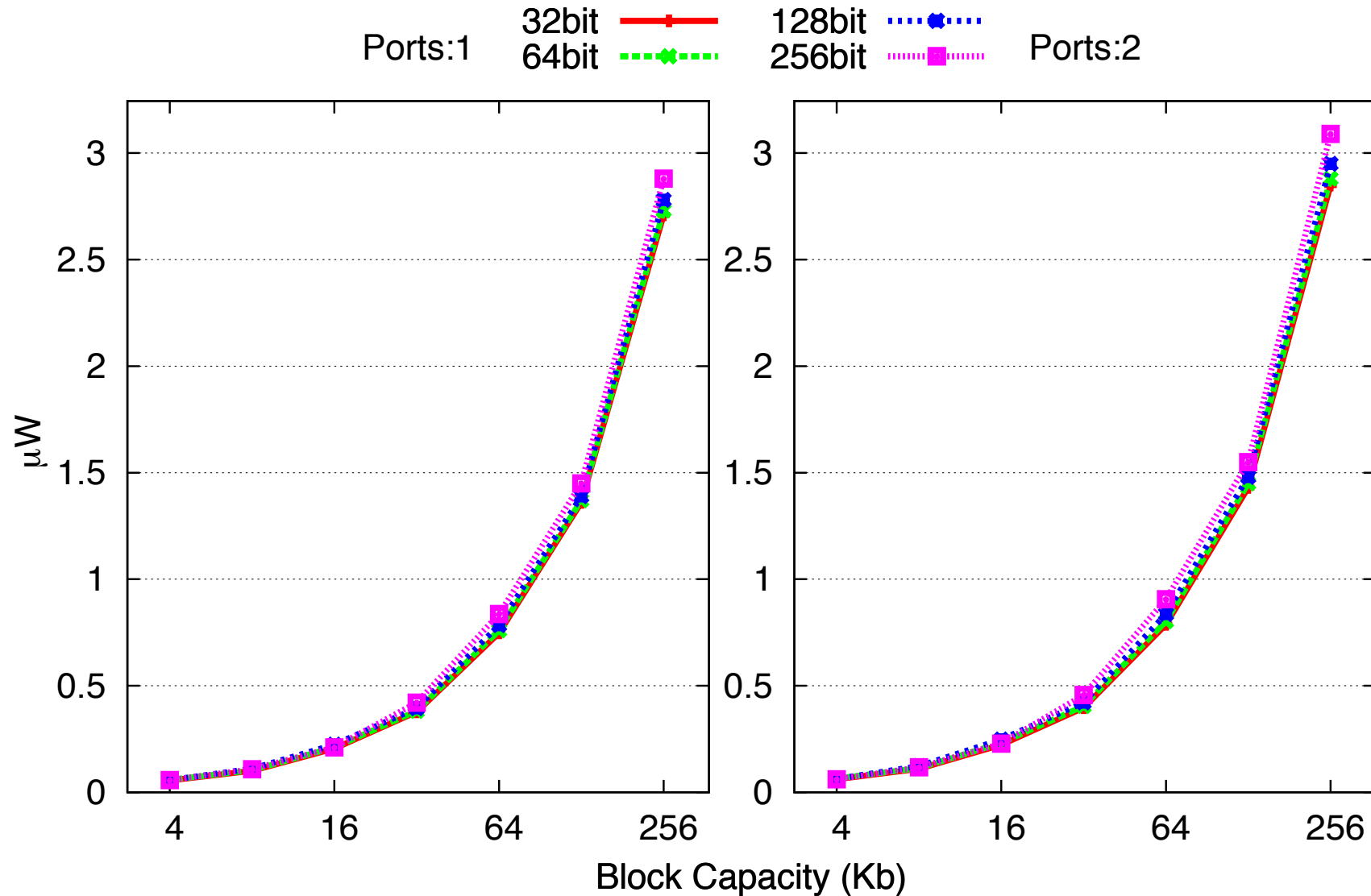


## Comments of Dynamic Power Consumption

- Dynamic power is consumed when nodes change state  $\Rightarrow$  proportional to access frequency:  $mW / GHz$
- Consumption increases with block size (squ. root of capacity) due to increasing word-line and bit-line capacitance
- Consumption increases with port-width (number of SA's)
- Two-port blocks: quoted consumption is per-port
- Two-port *total* consumption  $\approx 2x$  to  $3x$  consumption of 1-port
- Two-port blocks: one *read-only* port and one *write-only* port
- CACTI estimates, based on ITRS 2010 roadmap for 45 nm
- Low leakage power process assumed:  $V_{th} = 0.5 V$
- Typical-case consumption quoted;  $V_{DD} = 1.1 V, 60^\circ C$ 
  - all cycles active, all address and data bits switching

# SRAM (45 nm): Static (Leakage) Power Consumpt'n

Leak. Power vs Capacity, 45 nm, LSTP, Vdd: 1.1v, Vth: 0.502v

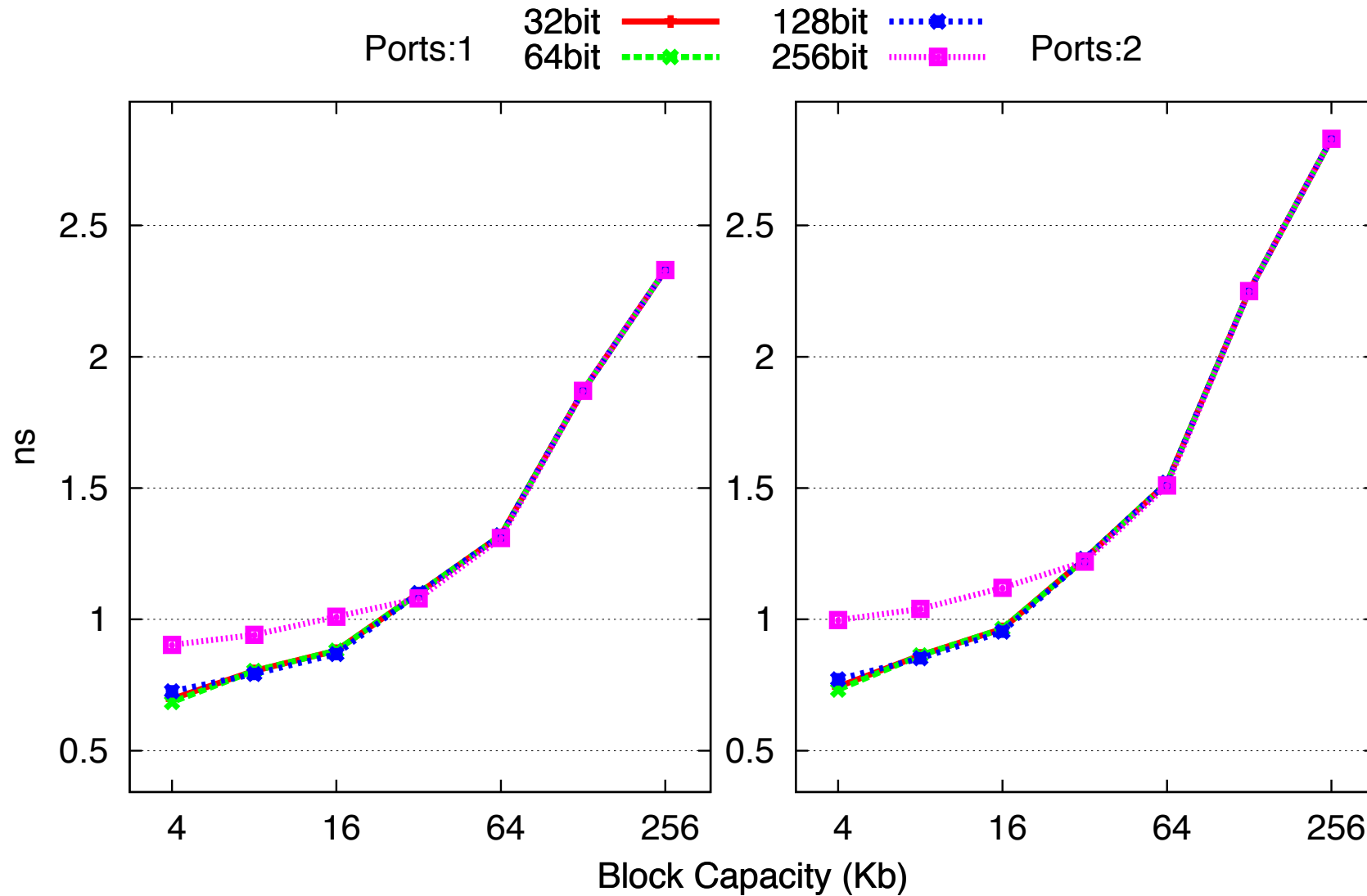


## Comments of Static (Leakage) Power Consumption

- Static power is consumed all the time, independent of activity, by leaky transistors that should be OFF but are not fully so
- Measured in micro-Watts, for the entire block
- Consumption is proportional to the number of transistors  
⇒ proportional to block capacity (Kbits)
- Consumption almost unaffected by port-width (not sure why)
- Two-port blocks: quoted consumption is for the entire block
- Two-port (total) consumption  $\approx + 5$  to 10% relative to 1-port (not sure why so little)
- CACTI estimates, based on ITRS 2010 roadmap for 45 nm
- Low leakage power process assumed (“LSTP”: low-standby power):  $V_{th} = 0.5$  V; typical-case cons’ptn:  $V_{DD} = 1.1$  V,  $60^{\circ}\text{C}$

# On-chip SRAM (45 nm CMOS): Cycle Time

Cycle time vs Capacity, 45 nm, LSTP, Vdd: 1.1v, Vth: 0.502v



## Cycle Time (1/AccessRate): Comments

- *Small is Fast*: small blocks are faster than large blocks
  - bit-line (and word-line) capacitance increases with length
  - for large capacities, beyond about 64 Kb, it is faster to use multiple small blocks, perhaps with external data-out mux after them, than to use a single large block
- Speed is almost independent of port width
  - except for small blocks that are excessively wide
- Two-port SRAM is  $\approx 20\%$  slower than 1-port
- CACTI estimates, based on ITRS 2010 roadmap for 45 nm
- Low-leakage-power process assumed:  $V_{th} = 0.5 \text{ V}$
- High-performance process would give 2x to 4x higher speed
- Typical-case speed quoted;  $V_{DD} = 1.1 \text{ V}$ ,  $60^\circ\text{C}$

## On-Chip SRAM Buffer Example 1 of 2: 40-Byte wide

- Width = 1 min-size IP packet = 40 Bytes = 320 bits =  
= 5 blocks × 64 bits/block
- One-Port, 2048 packets × 40 B/pck = 80 KB = 640 Kb
- 45 nm CMOS, 1.1 Volt, low-leakage (static) power process
- Area = 5 banks × 128 Kb/bank × 0.44 mm<sup>2</sup>/Mb =  
= 0.64 Mb × 0.44 mm<sup>2</sup>/Mb ≈ 0.3 mm<sup>2</sup>
- Throughput = 320 bits × 0.54 Gaccesses/s ≈ 170 Gb/s
- Dynamic Power Consumption =  
= 5 banks × 17.5 mW/GHz × 0.54 GHz = 47 mW
- Static Power = 5 banks × 0.0015 mW/bank = negligible  
(would be ~50 mW in a high-performance process!)

## On-Chip SRAM Buffer Example 2 of 2: 256-Byte wide

- Width  $\approx$  1 average-size IP packet = 256 Bytes = 2048 bits =  
= 64 blocks  $\times$  32 bits/block
- Two-Port, 2048 packets  $\times$  256 B = 512 KB = 4 Mb
- 45 nm CMOS, 1.1 Volt, low-standby-power process
- Area = 64 banks  $\times$  64 Kb/bank  $\times$  0.9 mm<sup>2</sup>/Mb =  
= 4 Mb  $\times$  0.9 mm<sup>2</sup>/Mb  $\approx$  **3.5 mm<sup>2</sup>**
- Throughput = 2 ports  $\times$  2048 b/port  $\times$  650 MHz  $\approx$  **2.6 Tb/s**  
(1300 Gb/s writes + 1300 Gb/s reads)
- Power Consumption =  
= 64 banks  $\times$  2 ports  $\times$  11 mW/GHz  $\times$  0.65 GHz  $\approx$  **0.9 W**
- **Conclusion:** “no problem” on-chip, except for short packets



## Power Cons./Throughput (1 of 2): on-chip **SRAM**

- Consider some “usual, medium-size” SRAM’s (45nm, LSTP):
  - 1-port, ×32:  $\approx 10 \text{ mW/GHz} = 10 \text{ mW} / 32 \text{ Gbps} \approx 0.31 \text{ mW/Gbps}$
  - 1-port, ×64:  $\approx 16 \text{ mW/GHz} = 16 \text{ mW} / 64 \text{ Gbps} \approx 0.25 \text{ mW/Gbps}$
  - 1-port, ×128:  $\approx 30 \text{ mW/GHz} = 30 \text{ mW} / 128 \text{ Gbps} \approx 0.23 \text{ mW/Gbps}$
  - 2-port, ×32:  $\approx 12 \text{ mW/GHz} = 12 \text{ mW} / 32 \text{ Gbps} \approx 0.38 \text{ mW/Gbps}$
  - 2-port, ×64:  $\approx 20 \text{ mW/GHz} = 20 \text{ mW} / 64 \text{ Gbps} \approx 0.31 \text{ mW/Gbps}$
- Conclusion: **0.2 to 0.4 mW/Gbps** power consumption  
for on-chip buffer memories

## Power Cons./Throughput (2 of 2): Chip I/O

- High-speed serial off-chip transceiver  $\approx$  12 to 35 mW/Gbps
  - differential pair, 8b/10b encoding
  - e.g. Xilinx Virtex 7 (28 nm CMOS): 260 mW for 12.5 GBaud transceiver i.e. 10 Gbps xmit + 10 Gbps rcv; or 200 mW for 6.25 Gbaud (5+5 Gbps); or 170 mW for 3.125 GBaud (2.5+2.5 Gbps)

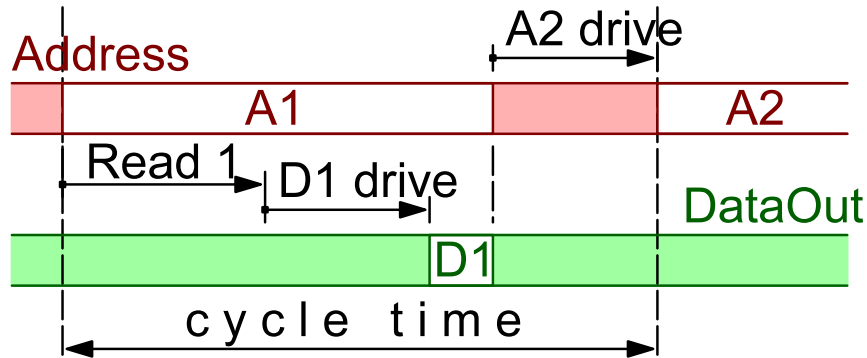
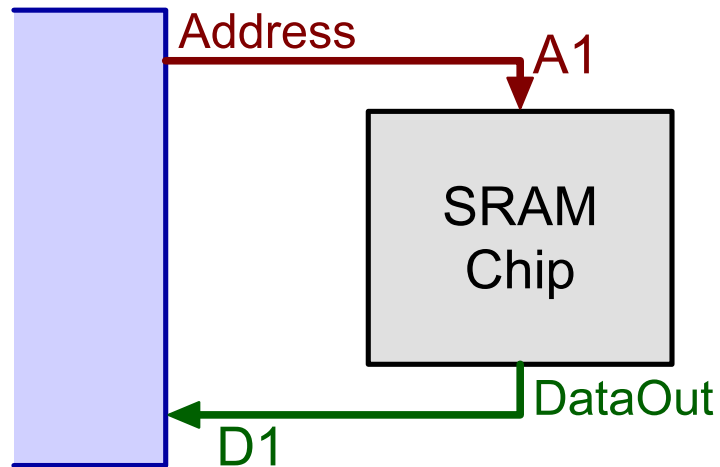
⇒ **Conclusion:** chip-to-chip communication costs one to two orders of magnitude more than on-chip buffering, in term of power consumption!

- Total chip power consumption (limited to  $\approx$  10 to 30 Watts) limits total chip throughput to about 1 Tbps/chip or less

## 2.2.2 Off-Chip SRAM Technologies

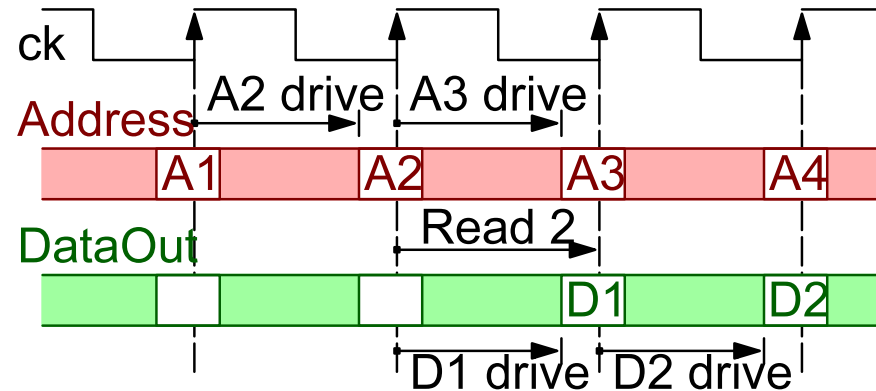
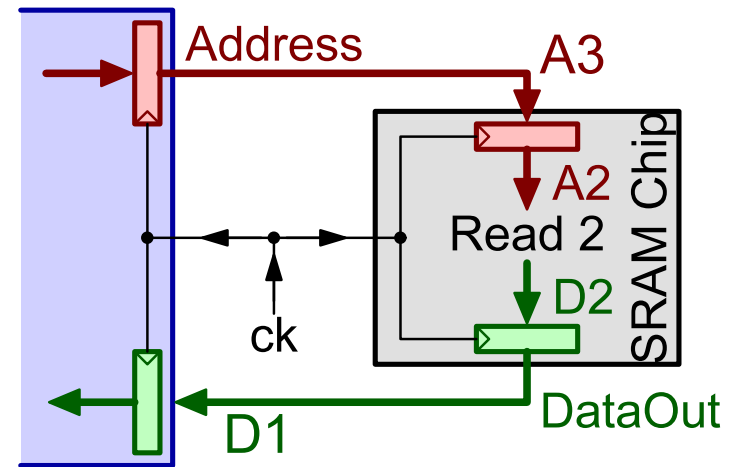
- Large on-chip throughput, owing to parallelism of accesses
- Gradual improvements in pin-interface protocols (late 90's):
  1. Clock-synchronous, pipelined address/data communication
  2. Double-Data Rate (DDR) data-pin timing (see §2.1)
  3. Source-synchronous clocking
    - clock signal propagating in the same direction as data (or address) signals – normally implies two separate clocks
  4. Separate, unidirectional Write-Data and Read-Data buses
    - avoids bus turn-around overhead, but
    - requires 50% writes – 50% reads for full utilization
  5. Write-data timing similar to read-data timing
    - first send the address, later send the data, so that address-bus to data-bus time-offset stays fixed for reads & writes

# Clock-Synchronous RAM: Pipelined Communication



*“Flow Through”*: old timing

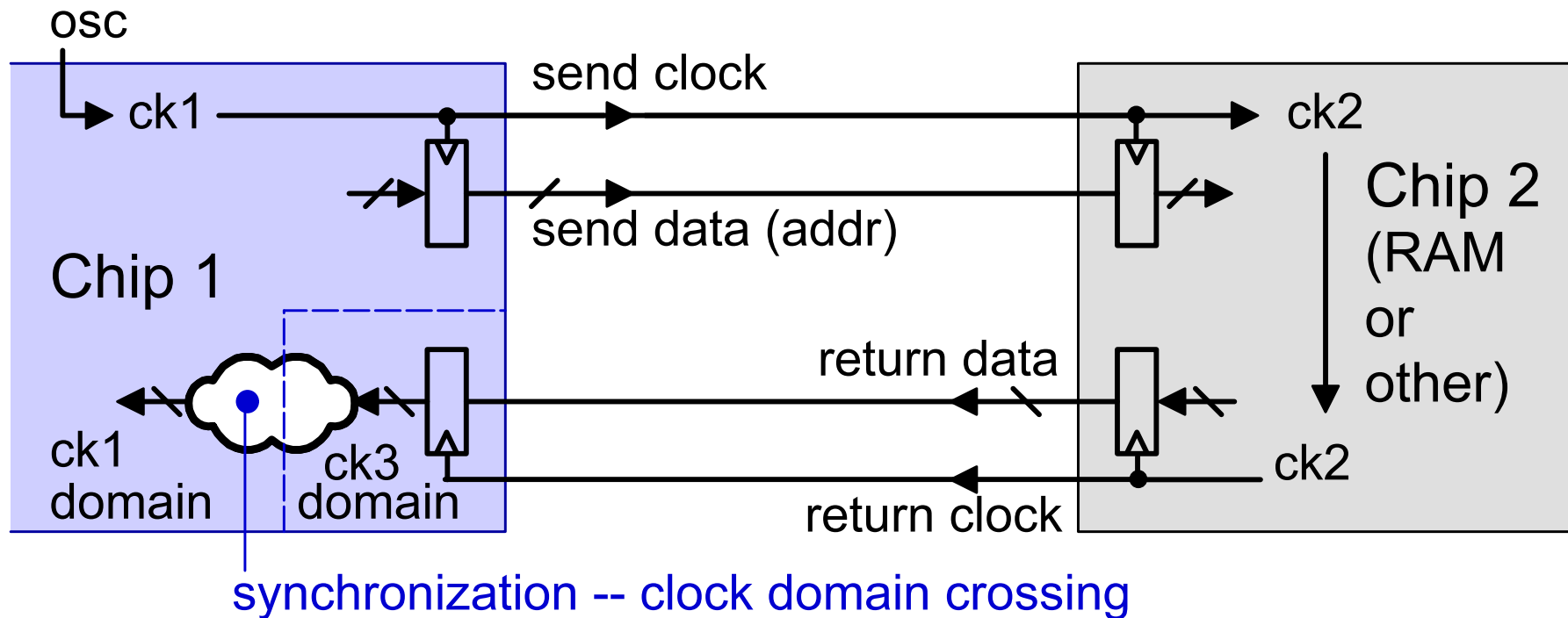
- no overlapping between SRAM operation and communication



*“Synchronous” Registered Interface*

- pipelined SRAM operation and chip-to-chip communication

## Source-Synchronous Data Clcking

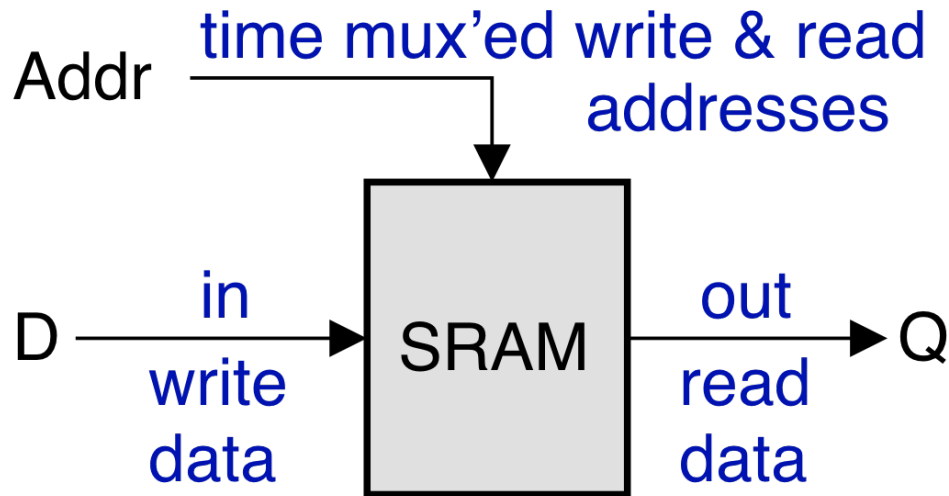


...further increasing the throughput of chip-to-chip communication:

- When the clock frequency rises, the chip-to-chip (speed-of-light) delay becomes non negligible w.r.t pulse width
- ck3 is a delayed version of ck1, i.e. has (exactly) the same frequency, but its delay (phase shift) may vary (slowly) with time

# SRAM Data I/O Paths

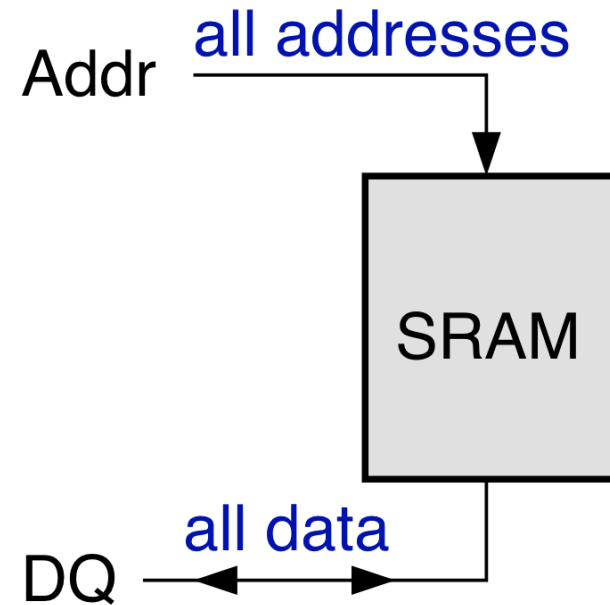
Separate D(in) & Q(out) Paths



Datapath underutilization when imbalanced ( $\neq 50 - 50\%$ ) read-write transactions

versus

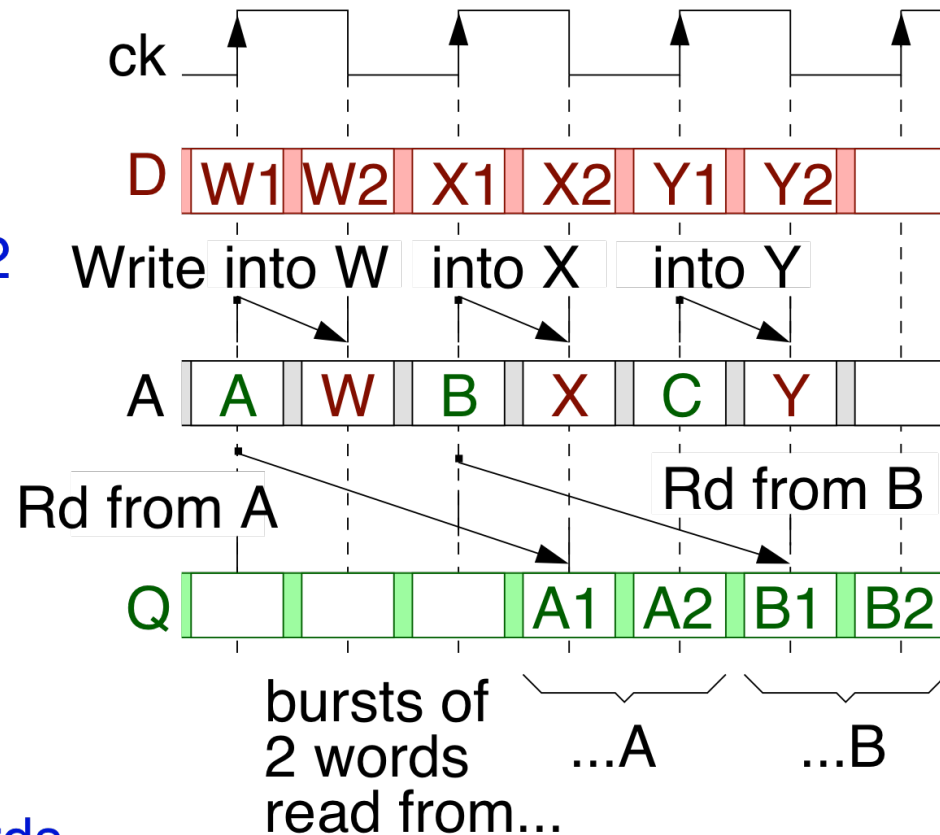
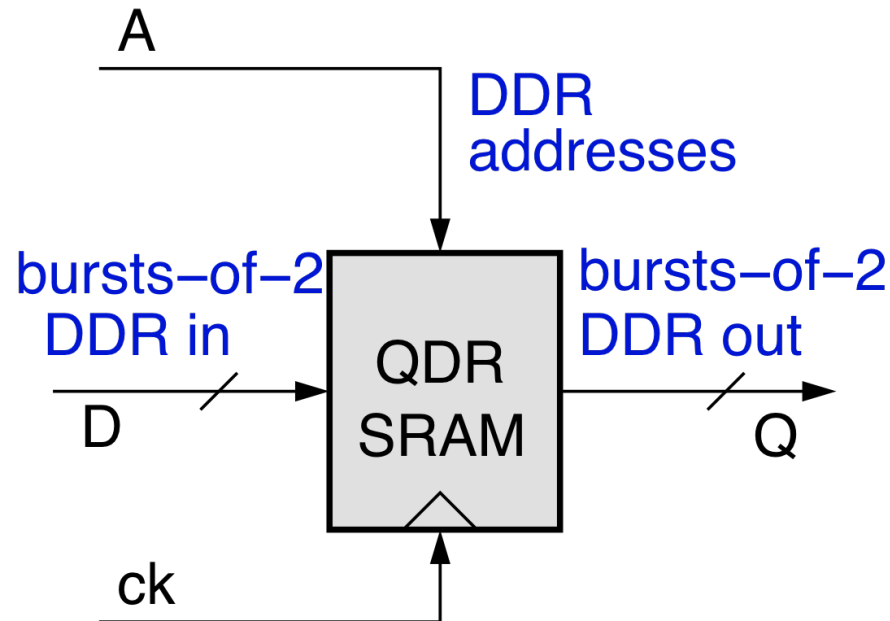
Shared DQ Data Bus



Bus turn-around overhead: Databus underutilization when frequently switching between read and write transactions

# “QDR” (Quad Data Rate) SRAM

Modern SRAM chip technology w. separate D(in) & Q(out) paths



## Other Version: "burst-of-4"

- addr. path is plain (NOT DDR)
- each addr. refers to 4 data words

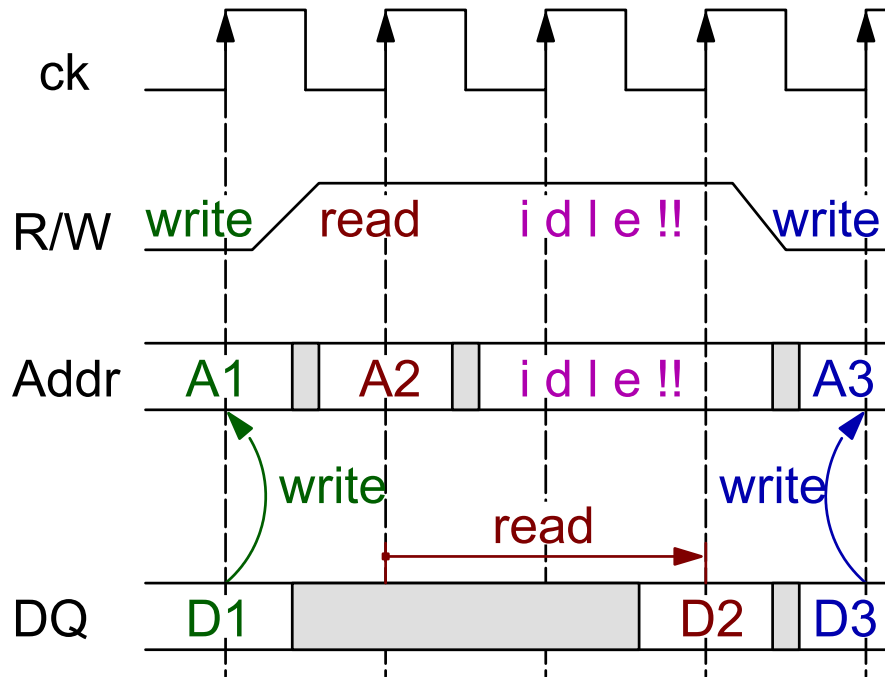
## Example QDR SRAM (2007): CY7C1545V18

- 72 Mbits = 4 M × 18 bits (width = 2 Bytes + parity/ECC)
- ≤ 375 MHz clock ⇒ cycle = 2.67 ns; bit-time = 1.33ns (DDR)
- Burst-of-4 words ↔ simple (non-DDR) address timing
- Peak Write Throughput:  
 $375 \text{ MHz} \times 2 \text{ (DDR)} \times 16 \text{ bits} = 12 \text{ Gb/s/chip} = 1.5 \text{ GB/s}$
- Peak Read Throughput = (similarly) 12 Gb/s
- Peak Total throughput *for balanced (50%-50%)* read-write:  
 $12 + 12 = \underline{24 \text{ Gb/s}} = 3 \text{ GB/s}$
- Power consumption ≈ 2.4 W (typical) @ 375 MHz, 1.8 Volt  
⇒ Power per throughput ≈ 2.4 W / 24 Gbps ≈ 100 mW/Gbps



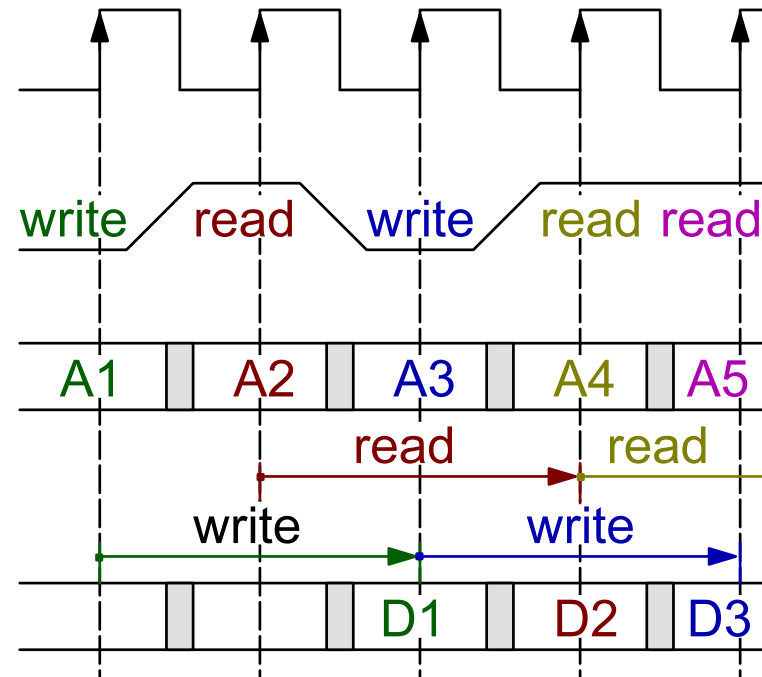
# Shared "DQ" Data Bus Timing

## Naïve Timing



Underutilization on every read-to-write transition

## "ZBT" (Zero Bus Turn Around) Timing



D1 has not yet been written at M[A1] when reading from M[A2] starts... → need to bypass mem. when  $A2=A1$

## Example Shared-Bus SRAM (2007): CY7C1550V18

- 72 Mbits = 2 M × 36 bits (width = 4 Bytes + parity/ECC)
- ≤ 375 MHz clock ⇒ cycle = 2.67 ns; bit-time = 1.33ns (DDR)
- Peak Throughput = 375 MHz × 2 (DDR) × 32 bits = 24 Gb/s
- “NoBL” (No Bus Latency) = “ZBT” (Zero Bus Turn-Around, ala Micron)
- Although NoBL/ZBT, one clock cycle is lost every time the bus direction changes from read to write (bus turn-around)
  - ⇒ throughput with alternating read/writes ≈  
≈ 2/3 × peak throughput ≈ 16 Gb/s
- Power consumption ≈ 2.4 W (typical) @ 375 MHz, 1.8 Volts
  - ⇒ Power per throughput ≈ 2.4 W / 24 Gbps ≈ 100 mW/Gbps

## 2.2.3 Dynamic RAM Chips and their Pin Interface

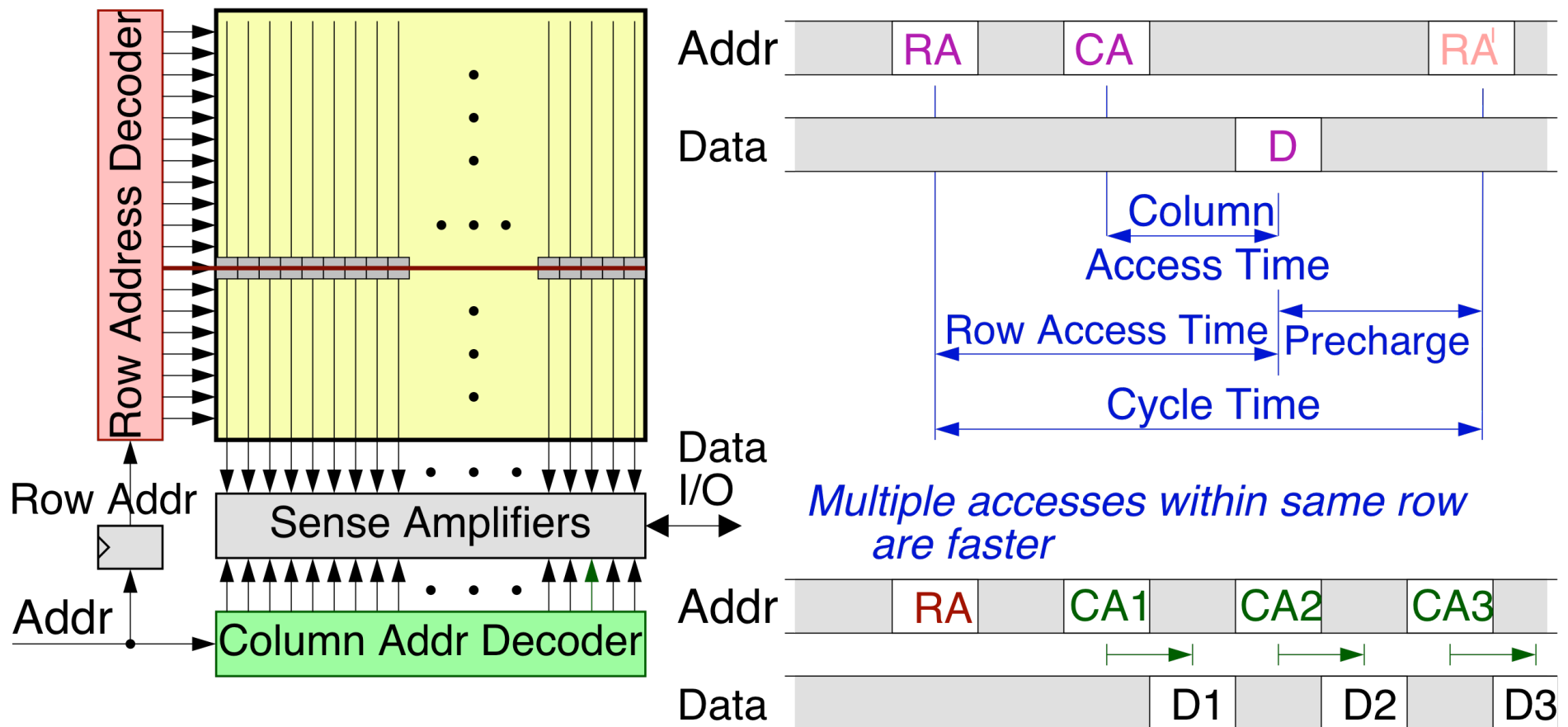
- Highest density and longest internal latency RAM chips
- Huge internal parallelism, when addresses are *favorable*:
  - multiple banks – memory interleaving
  - per-bank: entire *row* (hundreds of bits) accessed in parallel
- Pin Interface: advanced techniques to increase throughput
  - pins synchronized to a high-speed clock (Synchronous DRAM)
  - 100's of bits piped thru 10's of data pins during several clocks
  - internal RAM access is independent of clock – multiple cycles
- Three-step internal accesses – each bank independently
  - *row access*: activate a row in a bank, copy into sense amp's
  - *column access*: read/write multiple bits in selected row
  - *precharge*: get this bank ready for activating another row
- Address pins time-shared: row – column addr; multiple banks

## Example DDR3 SDRAM (2007): MT41J64M16

- $1 \text{ Gbit} = 64 \text{ M} \times 16 \text{ bits} = 8 \text{ banks} \times 8 \text{ Mw/bank} \times 16 \text{ b/w}$
- $\leq 800 \text{ MHz}$  clock
- Bidirectional data pins, DDR timing  $\Rightarrow$  up to 1.6 Gbps/pin
- Internal latencies specified as absolute times:
  - row-addr. to column-addr.  $\geq 14 \text{ ns}$
  - column-addr. to read-data  $\geq 14 \text{ ns}$
  - bank-cycle time  $\geq 48 \text{ ns}$ ; precharge time  $\geq 14 \text{ ns}$
- Translated to # of clock cycles by user @ boot time
  - e.g. at 800 MHz: row-acc  $\geq 11\sim$ , col-acc  $\geq 11\sim$ , bnk-cycle  $\geq 38\sim$
- (Remaining slides are for a much older chip (~2001)...)

# DRAM Basics:

## Row Address, Column Address, Precharge



## Fast DRAM Example (2001)

Micron MT46 V2 M32

DDR SDRAM

(Synchronous DRAM)

- 32-bit (shared DQ) databus, DDR timing  $\Rightarrow$   
 $\Rightarrow$  2 words  $\times$  32 bits each per clock cycle  
peak databus throughput

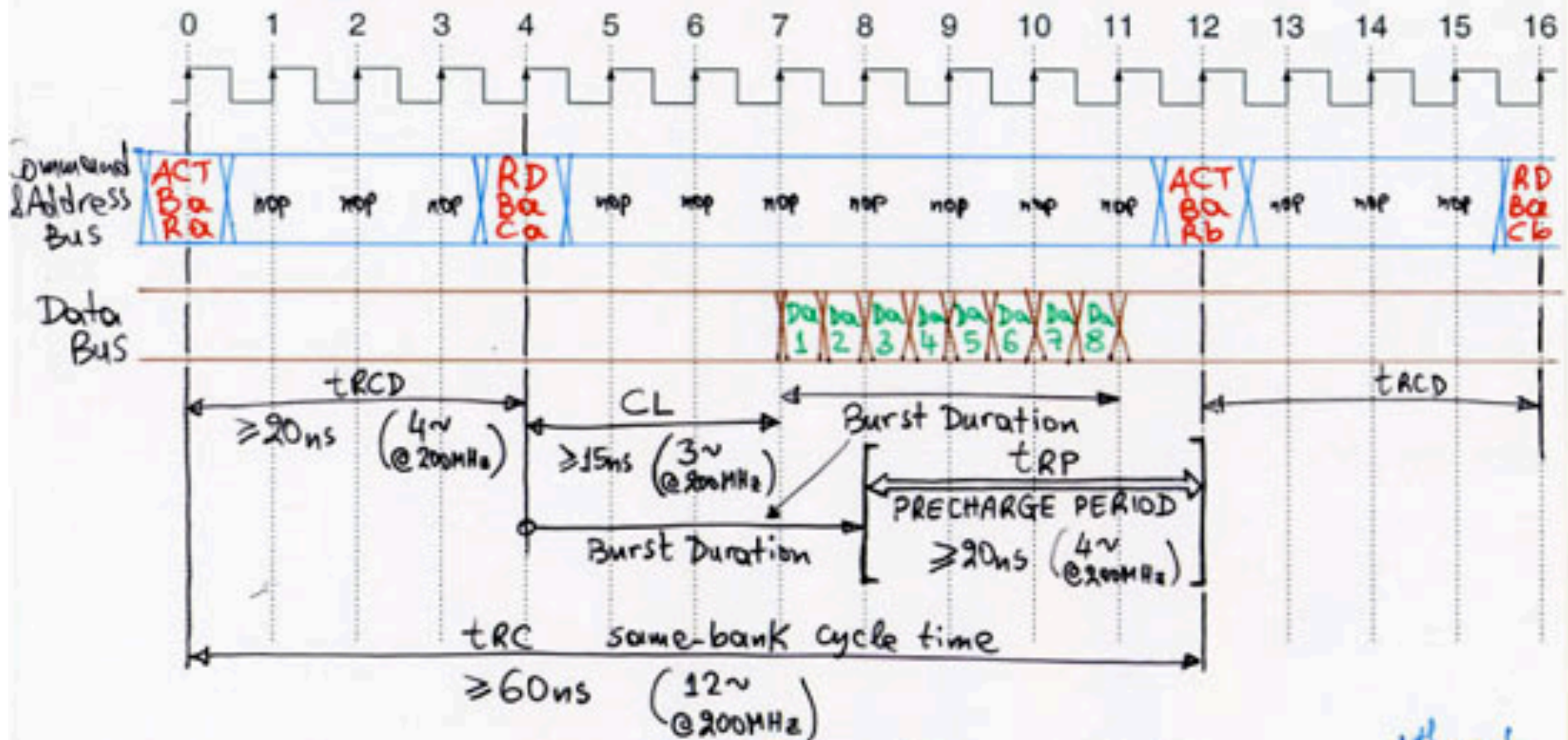
- Row Address - to - Column Address: .....  $t_{RCD} \geq 20\text{ns}$  (@200MHz: 4 $\sim$ )
- Column Address - to - Read Data (CAS latency): .....  $CL \geq 15\text{ns}$  (@200MHz: 3 $\sim$ )
- Write Recovery Time (write data - to - precharge): .....  $t_{WR} \geq$  ..... 2 $\sim$
- Precharge Time: .....  $t_{RP} \geq 20\text{ns}$  (@200MHz: 4 $\sim$ )
- Cycle Time (same bank): .....  $t_{RC} \geq 60\text{ns}$  (@200MHz: 12 $\sim$ )
- Bank - to - Bank Activation (other bank Row - to - Row):  $t_{RRD}$  ..... 2 $\sim$
- Read - to - Write bus turn-around lost cycles: ..... 3 $\sim$
- Write - to - Read same bank lost cycles (write recovery time): ..... 2 $\sim$
- Write - to - Read other bank lost cycles: .....  $\emptyset$  $\sim$

- 200 MHz max. clock frequency

- 64 Mbits = 2 M  $\times$  32 bits =  
= 512K  $\times$  32b  $\times$  4 Banks

- $\approx$  1 Watt at peak access rate,  
using one bank only, 2.5 Volt.  
(No number given for multibank op.)

# Single-Bank Read Access

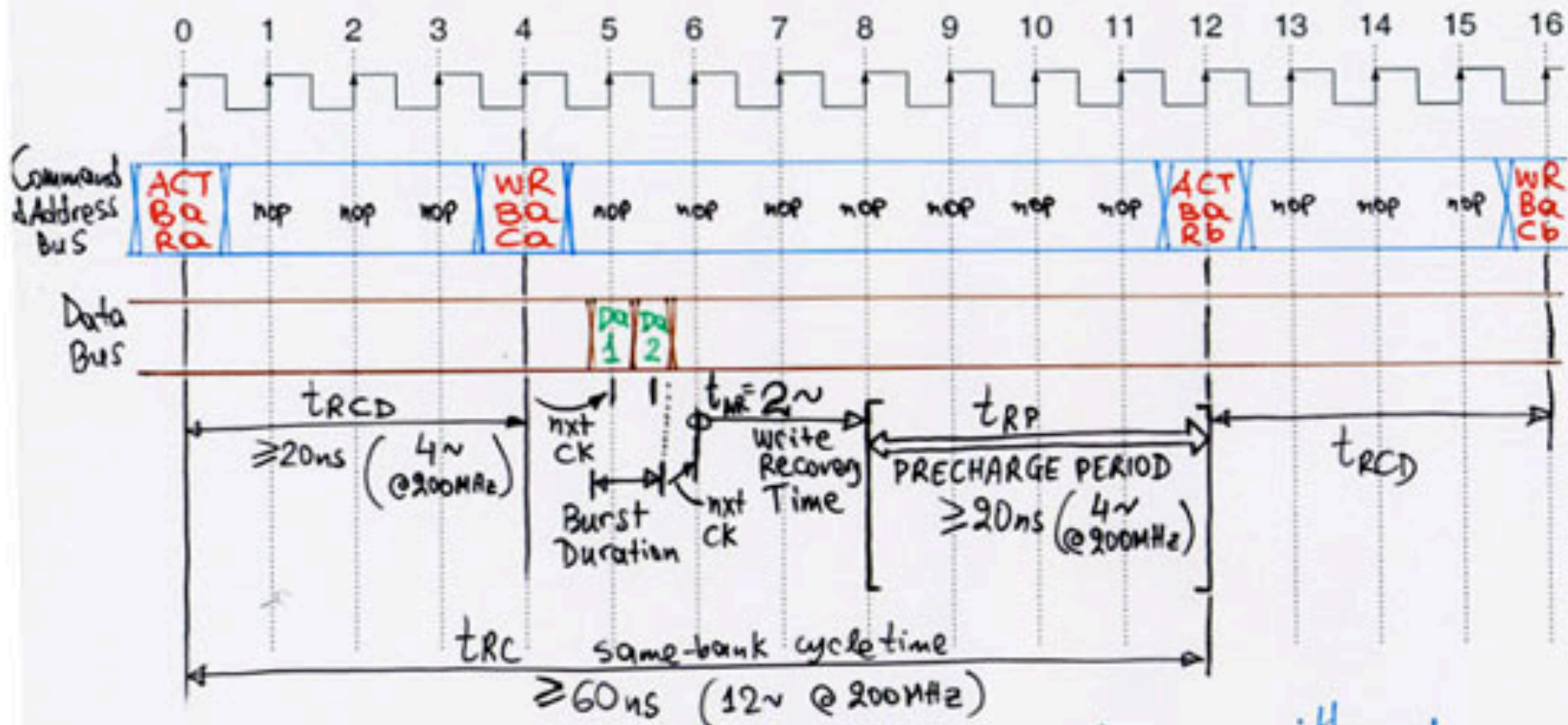


ACT = Activate  
 Ba = Bank #a  
 Ra = Row # Ra Address

RD = Read (the predefined burst size)  
 Ba = from the active Row within Bank #a  
 Ca = at Column Address #Ca

$D_i$  =  $i^{\text{th}}$  word of burst from  $B_a, R_a, C_a$

# Single-Bank Write Access



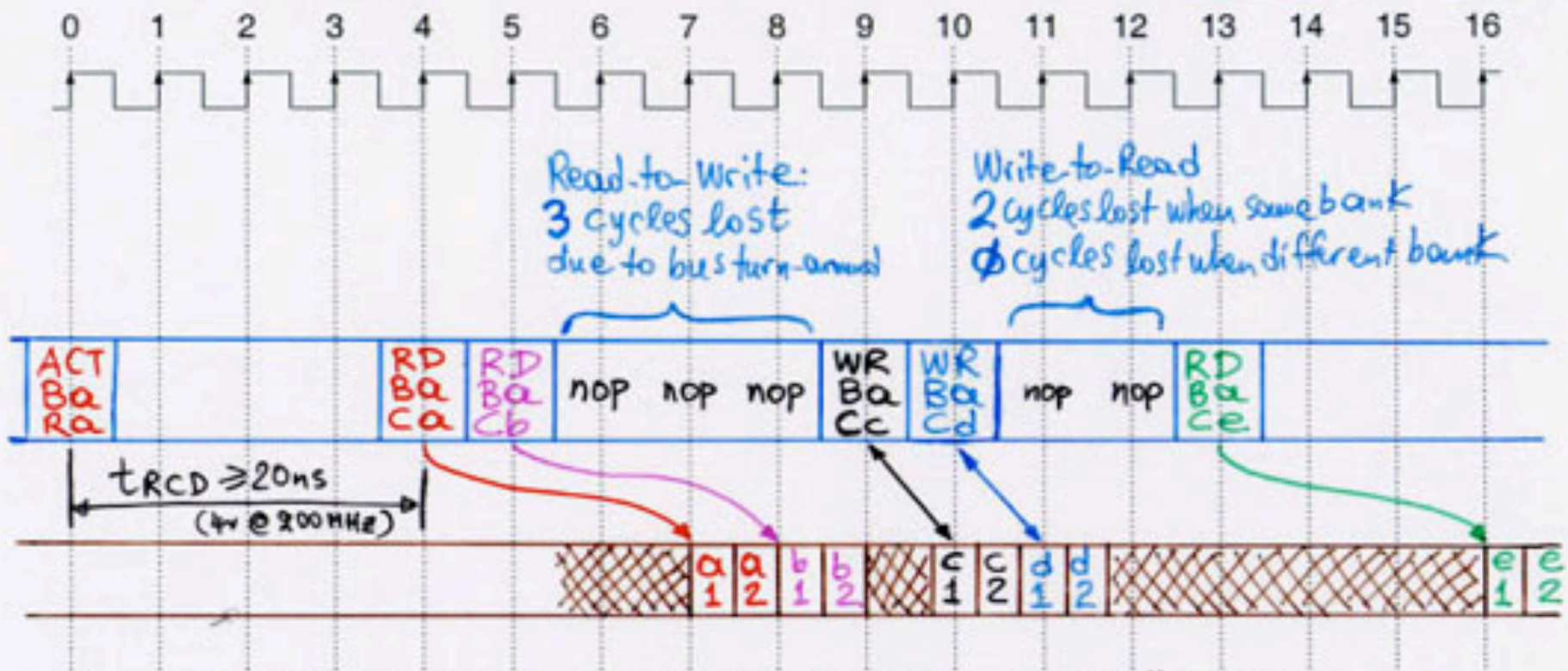
ACT = Activate  
 Ba = Bank #a  
 Ra = Row Address Ra

WR = Write (the predefined burst size)  
 Ba = into the active Row of Bank #a  
 Ca = at Column Address Ca

$D_{ai}$  =  $i^{\text{th}}$  word of burst destined to Ba, Ra, Ca



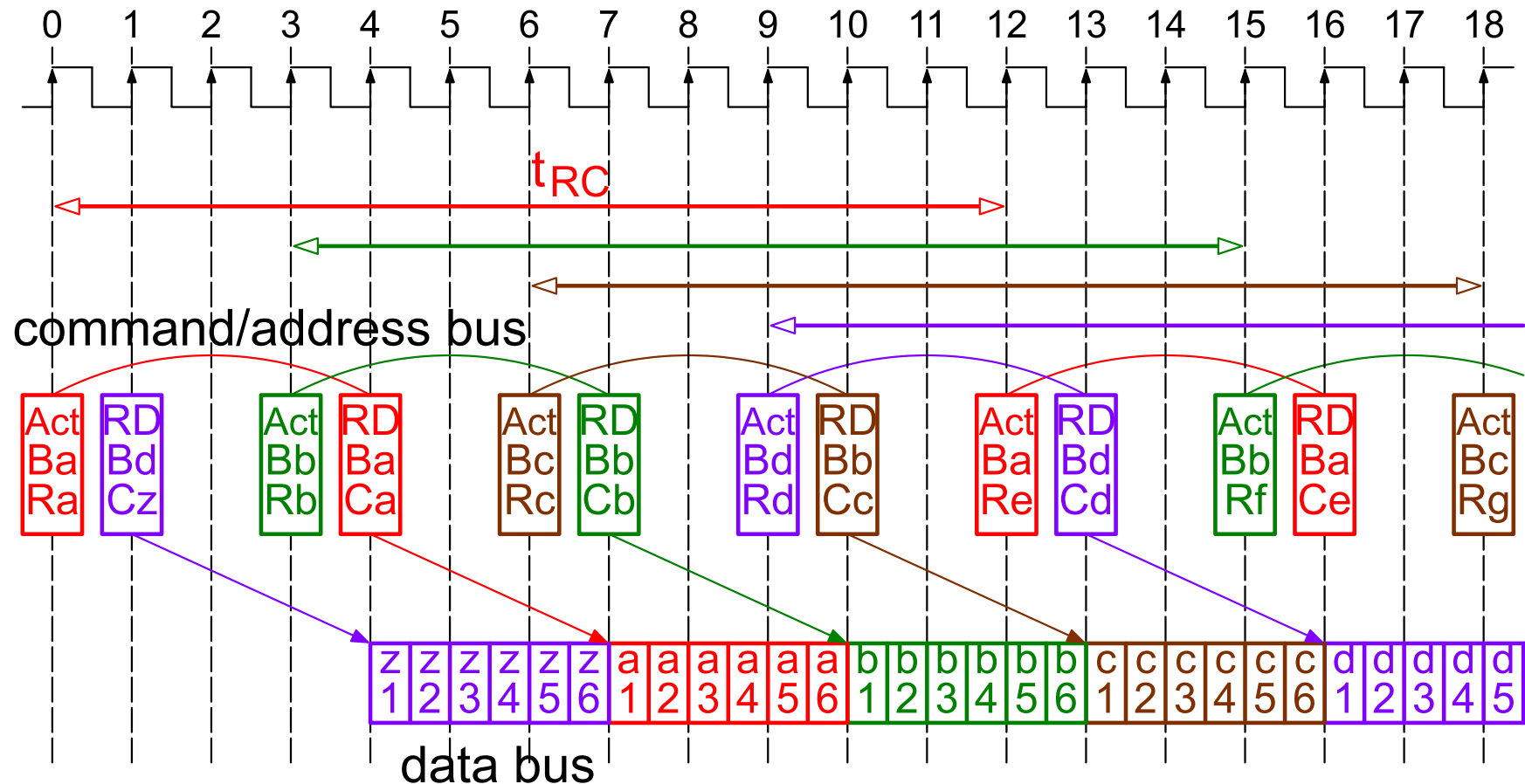
## Multiple Accesses to Different Columns in the same Row of a Bank



All transactions shown are to the same bank #a, and to the same activated row Ra in that bank.  
 The transactions shown are:

- Read from column Ca → a1, a2
- Read from column Cb → b1, b2
- Write c1, c2 at column Cc
- Write d1, d2 at column Cd
- Read from column Ce → e1, e2

## Multi-Bank Operation: Memory Interleaving



- burst length set to 8; each successive READ command interrupts the preceding burst, resulting in net bursts of 6.